### TABLE OF CONTENTS

CHAPTER	1 PRINCIPLES OF IMAGE FORMATION	J.M. COWLEY
11	Introduction	1
	Electron Scattering and Diffration	-
	The Physical Optics Analogy	
	Diffraction Patterns	
	Mathematical Formulation	
1.2	The Abbe Theory of Imaging	7
	Incident Beam Convergence	
	Chromatic Aberration	
	Mathematical Formulation	
1.3	Inelastic Scattering	12
1.4	STEM and CTEM	13
	STEM Imaging Modes	
	Mathematical Description	
1.5	Thin, Weakly Scattering Specimens	18
	Beam Convergence and Chromatic Aberration	
	Mathematical Formulation	
1.6	Thin, Strongly Scattering Specimens	23
	Mathematical Formulation	
1.7	Thin, Periodic Objects: Crystals	25
	Special Imaging Conditions	
	Mathematical Formulation	
1.8	Thicker Crystals	30
	Lattice Fringes	
	Mathematical Considerations	
1.9	Very Thick Specimens	34
	Mathematical Descriptions	
1.10	Conclusions	36
Classic	cal and General References	
Other	References	
CHAPTER	2 INTRODUCTORY ELECTRON OPTICS	R.H. GEISS
2.1	Introduction	43
2.2	Geometrical Optics	43
	Refraction	
	Cardinal Elements	
	Real and Virtual Images	
	Lens Equations	
	Paraxial Rays	
2.3	Electrostatic Lenses	49
	Refraction	
	Action of Electrostatic Lenses	
	Types of Electrostatic Lenses	

Contents
----------

2.4	Manual I and	<b>5</b> 0
2.4	Magnetic Lenses	53
	Action of an Inhomogeneous Field	
	Paraxial Ray Equations	
	Bell Shaped Field	
	Lens Excitation Parameters $\omega$ and $k^2$	
	Cardinal Elements of Magnetic Lenses	
	Ubjective Lenses	
	Special Magnetic Lenses	
2.5	Prism Optics	69
	Magnetic Sectors	
	Electrostatic Sectors	
	Wein Filter	
2.6	Optics of the Electron Microscope	72
	Electron Gun	
	Condenser Lens System	
	Coherence	
	Magnification Lens Systems	
2.7	Comparison of CTEM and STEM Optics	77
2.8	Conclusion	
Refer	ences	
CHAPTER	A 3 PRINCIPLES OF THIN FILM X-RAY MICROANALYSIS	J.I. GOLDSTEIN
3.1	Introduction	83
3.2	Quantitative X-ray Analysis	84
	Primary Emitted X-ray Intensities	
	Quantitative X-ray Analysis Using the Ration Technique and Thin Film Criter	ion
	Absorption Correction	
	Fluorescence Correction	
3.3	Spatial Resolution	100
	Analytical and Computer Models	
	Measurements of Spatial Resolution	
3.4	Sensitivity Limits	109
3.5	Summary	117
Ackn	owledgments	
Refer	ences	
СНАРТЕБ	4 OUANTITATIVE X-RAY MICROANALYSIS: INSTURMENT	AL NI ZALUZEC
	CONSIDERATIONS AND APPLICATIONS TO MATERIALS	SCIENCE
4.1	Introduction	121
4.2	Instrumental Limitations in AEM Based X-ray Microanalysis	121
4.3	Instrumental Artifacts: Systems Background	122
	Fluorescence by Uncollimated Radiation: Remote Sources	
	Fluorescence by Uncollimated Radiation: Local Sources	
	Specimen Contamination Detector Artifacts	
44	Ontimum Experimental Conditions for X-roy Analysis	120
7.7	Detector/Specimen Geometry	130
	Detector Collimation	
	Selection of Incident Beam Energy and Electron Source	
	Imaging and Diffraction Conditions During Analysis	
	Specimen reparation Artifacts	

4.5	Data Reduction for Quantitative Analysis	137
-----	--	-----

Contents		
4.6	Application of Quantitative X-ray Microanalysis: Parameters of Standardless Analysis Absorption Correction	139
4.7	Applications of Standardless Analysis Standardless Analysis Using the Thin-Film Approximation: Fe-1 3Cr-40Ni Standardless Analysis Using the Absorption Correction: NiA1	149
4.8	Standardless Analysis in Complex Systems Analysis of Totally Buried Peaks Quantitative Analysis of Precipitated Phases Procedures for Analysis of Radioactive Specimens	155
4.9	Summary	
Ackn	owledgments	
Refer	ences	
Table	S	
CHAPTE	<b>EDS QUANTITATION AND APPLICATION TO BIOLOGY</b>	T.A. Hall and B.L. GUPTA

#### 169 5.1 Introduction 170 5.2 Measurements on Thin or Ultrathin Sections Mounted on Thin Films **Elemental Ratios** Millimoles of Element Per Unit Volume Millimoles of Element Per kg of Dried Tissue (Continuum Method) Millimoles of Element Per kg Wet Weight (Continuum Method, Frozen-Hydrated Sections) Dry-Weight and Aqueous Fractions Conversion to mM of Element Per Litre of Water Absorption Corrections Standards 180 Effects of Contamination Within the Microscope Column 5.3 5.4 Effects of Beam Damage 181 5.5 Specimen Preparation 182 5.6 Specimens Other Than Sections Mounted on Thin Film 183 Main Literature References List of Symbols Used in this Article Subscripts References Appendix I Derivation of Equation 5.12 for Dry-Weight Determination Appendix II Sample Calculations Calculations

#### CHAPTER 6 MONTE CARLO SIMULATION IN ANALYTICAL ELECTRON MICROSCOPY DAVID F. KYSER 199 6.1 Introduction 6.2 Basic Physical Concepts in Monte Carlo Simulation 200 Electron Scattering Energy Loss Between Elastic Scattering Events Sequence of Calculations Spatial Distribution of Energy Loss and X-ray Production 6.3 Design, Implementation, and Output of a Monte Carlo Program 206 Computer Generation and Utilization of Random Numbers Computational Time and Its Control Condensation and Output of Results Obtained 6.4 Applications to X-ray Microanalysis 208 Depth Distribution of X-ray Production Total X-ray Production in Foils Radial Distribution of X-ray Production **Electron Trajectory Plotting**

Contents

9.3

Progress in Quantitation Analysis Methods

6.5       Summary Acknowledgments References       219         CHAPTER 7 THE BASIC PRINCIPLES OF ELECTRON ENERGY LOSS         SPECTROSCOPY       DAVID C / OV         7.1       What is Electron Energy Loss Spectroscopy?       223         7.3       What is Electron Energy Loss Spectroscopy?       223         7.3       What is Required?       223         7.3       What is Electron Energy Loss Spectrum       226         7.4       The Micro-Analytical Information in the EEL Specimen       227         Region 3- thigher Bergy Loss Spectrum       236         7.5       Collecting the Energy Loss Spectrum       236         7.6       Recording and Analyzing the Data       239         7.7       The Effects of Specimen Thickness       241         7.8       To Summarize       242         References       245       243         CHAPTER 8 ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL         RESEARCH       DALE E. JOHNSON         8.1       Introduction       245         8.3       Characteristics of a Typical Spectrum       246         8.3       General Microanalysis       247         Elemental Microanalysis       247         Elemental Microanalysis			Contents
References         CHAPTER 7 THE BASIC PRINCIPLES OF ELECTRON ENERGY LOSS         SPECTROSCOPY       DA VID C. JOY         7.1       What is Electron Energy Loss Spectroscopy?       223         7.2       What is Required?       223         7.3       Describing the Energy Loss Spectrum       225         7.4       The Micro-Analytical Information in the EEL Specimen       227         Region 1 - Around Zero-Loss       Region 2. The Low-Lose Region       236         7.5       Collecting the Energy Loss Spectrum       236         7.6       Recording and Analyzing the Data       239         7.7       The Effects of Specimen Thickness       241         7.8       To Summarize       242         References       242       References         CHAPTER 8 ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL         RESEARCH       DALE E. JOHNSON         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Chemical Microanalysis       248         Elemental Microanalysis       248         Belemental Microanalysis       248         M	6.5 Ackno	Summary wledgments	219
CHAPTER 7       THE BASIC PRINCIPLES OF ELECTRON ENERGY LOSS SPECTROSCOPY       DAVID C. JOY         7.1       What is Electron Energy Loss Spectroscopy?       223         7.2       What is Electron Energy Loss Spectrum       223         7.3       Describing the Energy Loss Spectrum       223         7.4       The Micro-Analytical Information in the EEL Specimen       227         Region 3- Higher Barry Loss Spectrum       236         7.5       Collecting the Energy Loss Spectrum       236         7.6       Recording and Analyzing the Data       239         7.7       The Effects of Specimen Thickness       241         7.8       To Summarize       242         References       DALE E. JOHNSON       445         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       248         Chemical Microanalysis       248         B.4       Approaches to the Quantitative Use of ELS       248         Elemental Microanalysis       249         Experimental Spectra       257         Low Z Elemental Mapping       257         References       2	Refere	nces	
CHAPTER 7 INE DASIC PRINCIPLES OF ELECTRON ENERGY LOSS SPECTROSCOPY DAVID C. 107 7.1 What is Electron Energy Loss Spectroscopy? 223 7.2 What is Required? 223 7.3 Describing the Energy Loss Spectrum 225 7.4 The Micro-Analytical Information in the EEL Specimen 227 Region 1 - Around Zero-Loss Region Region 2 - The Low-Loss Region Region 3 - The Low-Loss Region Region 3 - The Low-Loss Region Region 3 - The Energy Loss Spectrum 236 7.5 Collecting the Energy Loss Spectrum 236 7.6 Recording and Analyzing the Data 239 7.7 The Effects of Specimen Thickness 241 7.8 To Summarize 2422 References CHAPTER 8 ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL RESEARCH DALE E. JOHNSON 8.1 Introduction 245 8.2 Characteristics of a Typical Spectrum 245 8.3 Gensitivity of ELS Techniques 247 Elemental Microanalysis Chemical and Molecular Microanalysis 8.4 Approaches to the Quantitative Use of ELS 248 Elemental Microanalysis 8.5 Examples of Typical Experimental Results 249 Experimental Spectra Low Z Elemental Mapping Molecular Speciens 1 Mas Loss 1 is Bond Scission Speciment Misconalysis 8.7 Summary 257 References CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TEC	CUADTED	7 THE BACK DDINGING CORE I COTDOM ENERCY LOCK	
7.1       What is Electron Energy Loss Spectroscopy?       223         7.2       What is Required?       223         7.3       Describing the Energy Loss Spectrum       225         7.4       The Micro-Analytical Information in the EEL Specimen       227         Region 2: The Low-Loss Region       226         Region 2: The Low-Loss Region       236         7.5       Collecting the Energy Loss Spectrum       236         7.6       Recording and Analyzing the Data       239         7.7       The Effects of Specimen Thickness       241         7.8       To Summarize       242         References       242       245         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       247         Elemental Microanalysis       248         Chemical and Molecular Microanalysis       248         Molecular Microanalysis       249         Delectric Constant Determination       253         8.5       Examples of Typical Experimental Results       249         Extended Fine Structure (EXAFS)       249         Extended Fine Structur	CHAPTER	SPECTROSCOPY	DAVID C. JOY
1.1       That is Required?       223         7.2       What is Required?       223         7.3       Describing the Energy Loss Spectrum       225         7.4       The Micro-Analy tical Information in the EEL Specimen       227         Region 1 - Around Zero-Loss       Region 3 - Higher Energy Loss Spectrum       236         7.6       Recording and Analyzing the Data       239         7.7       The Effects of Specimen Thickness       241         7.8       To Summarize       242         References       242       References         CHAPTER 8       ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL RESEARCH       DALE E. JOHNSON         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       247         Chemical and Molecular Microanalysis       248         Elemental Microanalysis       248         Delectric Constant Determination       245         8.5       Practical Limitations       253         Radiation Damage       i Mas Loss       i Bond Specimen Thickness         i Effect on Background and Peak Heights       i Effect on Background and Peak Hei	71	What is Electron Energy Loss Spectroscony?	223
1.3     Describing the Energy Loss Spectrum     225       7.4     The Micro-Analytical Information in the EEL Specimen     227       Region 1 - Around Zero-Loss     Region 1 - Around Zero-Loss     227       Region 2 - The Low-Loss Region     236       7.5     Collecting the Energy Loss Spectrum     236       7.6     Recording and Analyzing the Data     239       7.7     The Effects of Specimen Thickness     241       7.8     To Summarize     242       References     242       CHAPTER 8 ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL       RESEARCH     DALE E. JOHNSON       8.1     Introduction     245       8.2     Characteristics of a Typical Spectrum     245       8.3     Sensitivity of ELS Techniques     247       Elemental Microanalysis     247       Elemental Microanalysis     248       Deleteric Constant Determination     248       Elemental Microanalysis     248       Deleteric Constant Determination     249       Experimental Spectra     249       Low Z Elemental Mapping     253       Radiation Damage     1       i Mass Loss     1       i Bond Stasion     253       Radiation Damage     257       References     257	7.1	What is Required?	223
7.4       The Micro-Analytical Information in the EEL Specimen       227         Region 1: Around Zero-Loss       Region 2: The Low-Loss Region       226         Region 3: Higher Energy Losses       336         7.5       Collecting the Energy Loss Spectrum       236         7.6       Recording and Analyzing the Data       239         7.7       The Effects of Specimen Thickness       241         7.8       To Summarize       242         References       CHAPTER 8       ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL         RESEARCH       DALE E. JOHNSON         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       248         Chemical Microanalysis       248         Chemical Microanalysis       249         Detectric Constant Determination       249         Experimental Spectra       249         Experimental Apping       253         Molecular Spectra Mapping       253         Refarences       253         8.6       Practical Limitations       253         Refarences       257         References	73	Describing the Energy Loss Spectrum	225
Region 3 - Higher Energy Loss       236         7.5       Collecting the Energy Loss Spectrum       236         7.6       Recording and Analyzing the Data       239         7.7       The Effects of Specimen Thickness       241         7.8       To Summarize       242         References       242         CHAPTER 8       ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL RESEARCH         DALE E. JOHNSON         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       Chemical and Molecular Microanalysis       248         Chemical And Molecular Microanalysis       248         Chemical Microanalysis       249         Molecular Microanalysis       249         Experimental Spectra       249         Experimental Spectra       253         Rediction Damage       i Mast Loss         i Bond Scission       Specimen Thickness         Specimen Thickness       257         References       Classic References         Classic References       253         Classic References       253         Classic	7.4	The Micro-Analytical Information in the EEL Specimen Region 1 - Around Zero-Loss Region 2 - The Low-Loss Region	227
7.5       Collecting the Energy Loss Spectrum       236         7.6       Recording and Analyzing the Data       239         7.7       The Effects of Specimen Thickness       241         7.8       TO Summarize       242         References       242         CHAPTER 8       ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL RESEARCH         NALL E. JOHNSON         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       Chemical and Molecular Microanalysis       248         Elemental Microanalysis       248       248         Elemental Microanalysis       249       248         Elemental Microanalysis       249       249         Experimental Spectra       249       253         Robit Constant Determination       253       253         8.6       Practical Limitations       253         8.7       Summary       257         8.8       References       253         8.6       Fractical Limitations       253         8.7       Summary       257         8.8       Referen		Region 3 - Higher Energy Losses	
7.6       Recording and Analyzing the Data       239         7.7       The Effects of Specimen Thickness       241         7.8       To Summarize       242         References       242         CHAPTER 8       ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL RESEARCH         DALE E. JOHNSON       245         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       248         Chemical and Molecular Microanalysis       248         Chemical Microanalysis       248         Dielectric Constant Determination       249         8.5       Examples of Typical Experimental Results       249         Experimental Spectra       249         Low Z Elemental Mapping       253         Molecular Species Mapping       253         8.6       Practical Limitations       253         8.7       Nummary       257         References       253       253         Classic References       257         References       259       250         Classic References       260         Classic Cons	7.5	Collecting the Energy Loss Spectrum	236
7.7       The Effects of Specimen Thickness       241         7.8       To Summarize       242         References       242         CHAPTER 8       ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL RESEARCH         DALE F. JOHNSON         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       247         Elemental Microanalysis       248         Chemical and Microanalysis       248         Chemical Microanalysis       248         Elemental Microanalysis       249         Experimental Spectra       249         Experimental Spectra       249         Experimental Spectra       249         Extended Fine Structure (EXAFS)       26         8.6       Practical Limitations       253         References       253         i Bond Scission       Specimen Thickness Effects in Mapping       257         References       253         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A         MICROANALYTICAL TECHNIQUE FOR MATERIALS       260         Spectrum       250 <td>7.6</td> <td>Recording and Analyzing the Data</td> <td>239</td>	7.6	Recording and Analyzing the Data	239
7.8       To Summarize       242         References       242         CHAPTER 8       ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL         RESEARCH       DALE E. JOHNSON         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       247         Chemical and Molecular Microanalysis       248         Elemental Microanalysis       248         Delectric Constant Determination       249         Experimental Spectra       249         Experimental Spectra       249         Low Z Elemental Microanalysis       249         Molecular Microanalysis       249         Molecular Microanalysis       249         Experimental Spectra       249         Experimental Spectra       253         Radiation Damage       1         i Boad Scission       253         Specimen Mass Thickness       257         References       253         Classic References       257         Classic References       257         Classic References       259         9.1       Introduction	7.7	The Effects of Specimen Thickness	241
References         CHAPTER 8       ENERGY LOSS SPECTROMETRY FOR BIOLOGICAL RESEARCH         DALE F. JOHNSON         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       248         Chemical and Molecular Microanalysis       248         Elemental Microanalysis       248         Dielectric Constant Determination       249         Experimental Spectra       249         Experimental Spectra       249         Extended Fine Structure (EXAFS)       26         8.6       Practical Limitations       253         Radiation Damage       i Mass Loss       i Bond Scission         Specimen Mass Thickness       i Effect on Background and Peak Heights       i Specimen Mass Thickness Effects in Mapping         8.7       Summary       257       257         References       Classic References       260         Classic References       260       259         9.1       Introduction       259         9.2       Basic Considerations       260         Spectrum       250       360 <td>7.8</td> <td>To Summarize</td> <td>242</td>	7.8	To Summarize	242
CHAPTER 8       ENERCY LOSS SPECTROMETRY FOR BIOLOGICAL RESEARCH       DALE E. JOHNSON         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       248         Chemical Molecular Microanalysis       248         Chemical Microanalysis       248         Chemical Microanalysis       249         Chemical Microanalysis       249         Delectric Constant Determination       253         Radiation Damage       1         i Bond Scission       253         Radiation Damage       1         i Speciment Mass Thickness Effects in Mapping       257         References       Classic References         Classic References       257         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALVTICAL TECHNIQUE FOR MATERIALS         9.1       Introduction       259         9.2       Basic Considerations Spectrum Dynamic Range Spectrum Dynamic Range       260	Refere	nces	
RESEARCH       DALE E. JOHNSON         8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       247         Chemical and Molecular Microanalysis       248         Chemical Microanalysis       248         Chemical Microanalysis       248         Chemical Microanalysis       248         Dielectric Constant Determination       249         Experimental Spectra       249         Examples of Typical Experimental Results       249         Extended Fine Structure (EXAFS)       253         8.6       Practical Limitations       253         Radiation Damage       i Mass Loss       i Specimen Thickness         i Bond Scission       Specimen Thickness       257         References       257       References         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION       259         9.1       Introduction       259         9.2       Basic Considerations       260         Spectrum Dynamic Range       260	CUADTED		
RESEARCH     DALE E. JOHNSON       8.1     Introduction     245       8.2     Characteristics of a Typical Spectrum     245       8.3     Sensitivity of ELS Techniques     247       Elemental Microanalysis     247       Chemical and Molecular Microanalysis     248       Elemental Microanalysis     248       Chemical Microanalysis     248       Chemical Microanalysis     248       Dielectric Constant Determination     249       8.5     Examples of Typical Experimental Results     249       Extended Fine Structure (EXAFS)     253       8.6     Practical Limitations     253       Radiation Damage     i Mass Loss     ii Bond Scission       Specimen Thickness     i Effect on Background and Peak Heights     ii Specimen Thickness       i i Bond Scission     Speciment Mass Thickness Effects in Mapping     257       References     Classic References     257       CHAPTER 9     ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION     259       9.1     Introduction     259       9.2     Basic Considerations Spectrum Dynamic Range Spectrum Dynamic Range     260	CHAPIER	8 ENERGY LUSS SPECTRUMETRY FOR BIOLOGICAL DESEADOU	
8.1       Introduction       245         8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       247         Chemical and Molecular Microanalysis       248         Elemental Microanalysis       248         Chemical Microanalysis       248         Chemical Microanalysis       249         Dielectric Constant Determination       249         Experimental Spectra       249         Low Z Elemental Mapping       249         Molecular Species Mapping       253         Radiation Damage       i Mass Loss         i Bond Scission       Speciment Microanalysis         Speciment Mickenss       257         References       257         Classic References       257         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION       259         9.1       Introduction       259         9.2       Basic Considerations       260         Spectrum Dynamic Range Spectrum Dynamic Range       260		RESEARCH	DALE E. JOHNSON
8.2       Characteristics of a Typical Spectrum       245         8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       Chemical and Molecular Microanalysis       248         6.1       Chemical Microanalysis       248         Chemical Microanalysis       248         Chemical Microanalysis       249         Chemical Microanalysis       249         Dielectric Constant Determination       249         Experimental Spectra       249         Low Z Elemental Mapping       Molecular Spectra         Low Z Elemental Mapping       253         Rediation Damage       i Mass Loss         i Bond Scission       Specimen Thickness         specimen Mass Thickness Effects in Mapping       257         References       Classic References         Classic References       259         Sola Spectrum       259         9.1       Introduction       259         9.2       Basic Considerations       260         Spectrum       260         Spectrum       259         9.2       Basic Considerations       260         Spectrum       259         Spectrum       260         Spectrum       260	8.1	Introduction	245
8.3       Sensitivity of ELS Techniques       247         Elemental Microanalysis       Chemical and Molecular Microanalysis       248         Elemental Microanalysis       248         Elemental Microanalysis       248         Elemental Microanalysis       248         Elemental Microanalysis       249         Molecular Microanalysis       249         Experimental Spectra       249         Low Z Elemental Mapping       249         Molecular Species Mapping       249         Extended Fine Structure (EXAFS)       8.6         8.6       Practical Limitations       253         Radiation Damage       i Mass Loss       i Bond Scission         Specimen Thickness       i Effect on Background and Peak Heights       i Specimen Mass Thickness Effects in Mapping         8.7       Summary       257         References       Classic References       257         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION       DENNIS M. MAHER         9.1       Introduction       259         9.2       Basic Considerations Spectral Background       260         Spectrum Dynamic Range Spectrum Dynamic Range       260	8.2	Characteristics of a Typical Spectrum	245
Elemental Microanalysis Chemical and Molecular Microanalysis 8.4 Approaches to the Quantitative Use of ELS 248 Elemental Microanalysis Chemical Microanalysis Molecular Mapping Molecular Species Microanalysis Molecular Microanalysis Molecul	8.3	Sensitivity of ELS Techniques	247
Chemical and Molecular Microanalysis       248         Elemental Microanalysis       248         Chemical Microanalysis       248         Dielectric Constant Determination       249         Experimental Spectra       249         Low Z Elemental Mapping       249         Molecular Species Mapping       253         Radiation Damage       i Bond Scission         Specimen Thickness       257         References       Classic References         Classic References       257         References       Classic References         Classic References       259         9.1       Introduction       259         9.2       Basic Considerations       259         9.2       Basic Considerations       260         Spectrum       259       260         Spectrum       260		Elemental Microanalysis	
8.4       Approaches to the Quantitative Use of ELS       248         Elemental Microanalysis       Chemical Microanalysis       Molecular Microanalysis         Dielectric Constant Determination       8.5       Examples of Typical Experimental Results       249         Experimental Spectra       Low Z Elemental Mapping       Molecular Species Mapping       249         Extended Fine Structure (EXAFS)       8.6       Practical Limitations       253         Radiation Damage       i Mass Loss       i Bond Scission       253         si Bond Scission       Specimen Thickness       i Effect on Background and Peak Heights       257         References       Classic References       257         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A         MICROANALYTICAL TECHNIQUE FOR MATERIALS       DENNIS M. MAHER         9.1       Introduction       259         9.2       Basic Considerations       260         Spectrum       Dynamic Range       260         Spectrum       Dynamic Range       260		Chemical and Molecular Microanalysis	• ••
Chemical Microanalysis Molecular Microanalysis Dielectric Constant Determination 8.5 Examples of Typical Experimental Results Experimental Spectra Low Z Elemental Mapping Molecular Species Mapping Extended Fine Structure (EXAFS) 8.6 Practical Limitations Radiation Damage i Mass Loss ii Bond Scission Specimen Thickness i Effect on Background and Peak Heights ii Specimen Mass Thickness Effects in Mapping 8.7 Summary References Classic References CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION DENNIS M. MAHER 9.1 Introduction 9.2 Basic Considerations Spectrum Dynamic Range Spectrum Dynamic Range	8.4	Approaches to the Quantitative Use of ELS Elemental Microanalysis	248
Biolectric Constant Determination       249         S.5       Examples of Typical Experimental Results       249         Experimental Spectra       Low Z Elemental Mapping       Molecular Species Mapping         Molecular Species Mapping       Extended Fine Structure (EXAFS)       253         8.6       Practical Limitations       253         Radiation Damage       i Mass Loss       253         i Bond Scission       Specimen Thickness       1 Effect on Background and Peak Heights         i Specimen Mass Thickness Effects in Mapping       257         References       Classic References       257         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION       DENNIS M. MAHER         9.1       Introduction       259       259         9.2       Basic Considerations Spectrum Dynamic Range Spectrum Dynamic Range Spectrum Background       260		Chemical Microanalysis Molecular Microanalysis	
8.5       Examples of Typical Experimental Results       249         Experimental Spectra       Low Z Elemental Mapping       253         Molecular Species Mapping       Extended Fine Structure (EXAFS)       253         8.6       Practical Limitations       253         Radiation Damage       i Mass Loss       253         i Bond Scission       Specimen Thickness       257         References       Classic References       257         Classic References       Classic References       257         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION       DENNIS M. MAHER         9.1       Introduction       259         9.2       Basic Considerations Spectrum Dynamic Range Spectrum       260		Dielectric Constant Determination	
Experimental Spectra         Low Z Elemental Mapping         Molecular Species Mapping         Extended Fine Structure (EXAFS)         8.6       Practical Limitations         Radiation Damage         i Mass Loss         ii Bond Scission         Specimen Thickness         i Effect on Background and Peak Heights         ii Specimen Mass Thickness Effects in Mapping         8.7       Summary         257         References         Classic References         Classic References         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION         9.1       Introduction       259         9.2       Basic Considerations Spectrum Dynamic Range Spectrum Dynamic Range Spectrum       259	8.5	Examples of Typical Experimental Results	249
Low Z Elemental Mapping Molecular Species Mapping Extended Fine Structure (EXAFS) 8.6 Practical Limitations 253 Radiation Damage i Mass Loss ii Bond Scission Specimen Thickness i Effect on Background and Peak Heights ii Specimen Mass Thickness Effects in Mapping 8.7 Summary 257 References Classic References CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION DENNIS M. MAHER 9.1 Introduction 259 9.2 Basic Considerations 260 Spectrum Dynamic Range Spectrum Background		Experimental Spectra	
Molecular Species Mapping Extended Fine Structure (EXAFS)       253         8.6       Practical Limitations       253         Radiation Damage       i Mass Loss       i Bond Scission         Specimen Thickness       i Bond Scission       Specimen Thickness         i Bond Scission       Specimen Mass Thickness Effects in Mapping       257         References       Classic References       257         Classic References       Classic References       257         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION       DENNIS M. MAHER         9.1       Introduction       259         9.2       Basic Considerations Spectrum Dynamic Range Spectral Background       260		Low Z Elemental Mapping	
8.6       Practical Limitations       253         Radiation Damage       i Mass Loss       i Bond Scission         Specimen Thickness       i Effect on Background and Peak Heights       ii Specimen Mass Thickness Effects in Mapping         8.7       Summary       257         References       Classic References       257         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION       DENNIS M. MAHER         9.1       Introduction       259         9.2       Basic Considerations Spectrum Dynamic Range Spectrum Dynamic Range Spectrum Dynamic Range Spectrum       260		Molecular Species Mapping Extended Fine Structure (FXAES)	
0.00       Filiation Damage       250         Radiation Damage       i Mass Loss       1         i Mass Loss       ii Bond Scission       Specimen Thickness         i Effect on Background and Peak Heights       ii Specimen Mass Thickness Effects in Mapping       257         8.7       Summary       257         References       Classic References       257         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION       DENNIS M. MAHER         9.1       Introduction       259         9.2       Basic Considerations Spectrum Dynamic Range Spectrum Dynamic Range Spectrum       260	86	Practical Limitations	253
i Mass Loss ii Bond Scission Specimen Thickness i Effect on Background and Peak Heights ii Specimen Mass Thickness Effects in Mapping 8.7 Summary 257 References Classic References CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION DENNIS M. MAHER 9.1 Introduction 259 9.2 Basic Considerations 260 Spectrum Dynamic Range Spectrum	0.0	Radiation Damage	200
ii Bond Scission Specimen Thickness i Effect on Background and Peak Heights ii Specimen Mass Thickness Effects in Mapping 8.7 Summary 257 References Classic References CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION DENNIS M. MAHER 9.1 Introduction 259 9.2 Basic Considerations 260 Spectrum Dynamic Range Spectral Background		i Mass Loss	
Specimen Thickness i Effect on Background and Peak Heights ii Specimen Mass Thickness Effects in Mapping 8.7 Summary 257 References Classic References CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION DENNIS M. MAHER 9.1 Introduction 259 9.2 Basic Considerations 260 Spectrum Dynamic Range Spectral Background		ii Bond Scission	
ii Specimen Mass Thickness Effects in Mapping       257         8.7 Summary       257         References       Classic References         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION         9.1       Introduction       259         9.2       Basic Considerations Spectrum Dynamic Range Spectral Background       260		Specimen Thickness i Effect on Background and Peak Heights	
8.7       Summary       257         References       Classic References       257         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION       DENNIS M. MAHER         9.1       Introduction       259         9.2       Basic Considerations Spectrum Dynamic Range Spectral Background       260		i Specimen Mass Thickness Effects in Mapping	
References         Classic References         CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION         9.1       Introduction         9.2       Basic Considerations Spectrum Dynamic Range Spectral Background	8.7	Summary	257
Classic References CHAPTER 9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION DENNIS M. MAHER 9.1 Introduction 259 9.2 Basic Considerations Spectrum Dynamic Range Spectral Background	Refere	nces	
CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION         9.1       Introduction         9.2       Basic Considerations Spectrum Dynamic Range Spectral Background	Classic	References	
CHAPTER 9       ELEMENTAL ANALYSIS USING INNER-SHELL EXCITATIONS: A MICROANALYTICAL TECHNIQUE FOR MATERIALS CHARACTERIZATION       DENNIS M. MAHER         9.1       Introduction       259         9.2       Basic Considerations Spectrum Dynamic Range Spectral Background       260			
MICROARACTERIZATION     DENNIS M. MAHER       9.1     Introduction     259       9.2     Basic Considerations     260       Spectrum     Dynamic Range       Spectral Background	CHAPTER	9 ELEMENTAL ANALYSIS USING INNER-SHELL EXCITA MICROANALYTICAL TECHNIQUE FOR MATERIALS	FIONS: A
9.1     Introduction     259       9.2     Basic Considerations     260       Spectrum     Dynamic Range     Spectral Background		CHARACTERIZATION	DENNIS M MAHED
9.1Introduction2599.2Basic Considerations260SpectrumDynamic RangeSpectral BackgroundSpectral Background			DENNIS M. MANEK
9.2 Basic Considerations 260 Spectrum Dynamic Range Spectral Background	9.1	Introduction	259
Spectrum Dynamic Range Spectral Background	9.2	Basic Considerations	260
Dynamic Kange Spectral Background		Spectrum Descenti Bases	
		Spectral Background	

Speci	rai back	g
Edge	Shapes	

х

	Method 1: Efficiency Factors Method 2: Calculated Partial Cross Sections Method 3: Standards Tests of Analysis Methods Stability of Quantitation Methods Relative Accuracy of Atomic Ratios Absolute Accuracy of Quantitation Future Considerations	
9.4	Elemental Identification Threshold Energy Shape Analysis Elemental Maps	281
9.5	Detection Limits Importance of β Minimum Detectable Limits	285
9.6	Summary	287
Refer	ences	
CHAPTER	<b>ANALYSIS OF THE ELECTRONIC STRUCTURE OF SOLIDS</b>	JOHN SILCOX
10.1	Introduction	295
10.2	Scattering Kinematics	296
10.3	Inner-Core Excitations	300
10.4 Einal	Valence Electron Excitations	502
Ackn	nwledgments	
Refer	ences	
CHAPTER	TI STEM IMAGING OF CRYSTALS AND DEFECTS	C.J. HUMPHREYS
11.1	Introduction	305
11.2	Principle of Reciprocity in STEM and CTEM	306
	Reciprocity of Electron Microscopes	
	The Inapplicability of Reciprocity for Thick Specimens	
	Qualitative Reciprocity of the Top-Bottom Effect	
	Procedure if Reciprocity is not Applicable	
11.3	Image Recording and Signal/Noise	310
	Signal/Noise and Reciprocity	
114	Z-contrast Applied to Materials The Ontimum Ream Divergences for Imaging Crystal Defects	317
11.4	Typical Values of $\alpha$ and $\beta$ in CTEM and STEM	512
	Effects of Varying $\beta_s$ on STEM Images	
	Two-Beam Dynamical Theory Interpretation	
	Choice of Optimum $\beta_s$ Value	
11.5	The Identification of Crystal Defects	317
	Properties of Dislocation Images	
11.6	The Breakdown of the Column Approximation in STEM	320
	The Nature of the Column Approximation	
	High Resolution STEM Image Calculations Without the Column Approximation	
11.7	Penetration in Crystals Using CTEM and STEM	323
	Example of Penetration of CTFM (W Filement)	
	Penetration in STEM	
	The Penetration in STEM and CTEM	
	The Top-Bottom Effect	

265

Contents

11.8	Current Developments in the STFM Imaging of Defects	327
11.0	Post Specimen Lenses	521
	On-Line Optical Image Processing	
	Lattice Imaging	
	High Voltage STEM	
Ackno	wedoments	
Refere	nces	
Classic	al References	
		T
HAPIEK	12 BIOLOGICAL SCANNING TRANSMISSION ELECTRON MICROSCOPY	N
	MICROSCOPT	J. WALL
12.1	Introduction	333
12.2	Quantitative Measurement with the STEM	335
	Length	
	Mass	
	Substrate Noise	
	Resolution	
	Specimen Modification During Imaging	
12.3	Conclusion	341
Ackno	wledgments	
Refere	nces	
HAPTER	13 ELECTRON MICROSCOPY OF INDIVIDUAL	
	ATOMS M. ISAACSON, M.O.	HTSUKI and M. UTLAUT
13.1	ATOMS M. ISAACSON, M.O.I Introduction	HTSUKI and M. UTLAUT 343
13.1 13.2a	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering	HTSUKI and M. UTLAUT 343 344
13.1 13.2a 13.2b	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation	HTSUKI and M. UTLAUT 343 344 346
13.1 13.2a 13.2b 13.3a	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics	HTSUKI and M. UTLAUT 343 344 346 347
13.1 13.2a 13.2b 13.3a	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation	HTSUKI and M. UTLAUT 343 344 346 347
13.1 13.2a 13.2b 13.3a	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Provide Constitutions of Stations Depending	HTSUKI and M. UTLAUT 343 344 346 347
13.1 13.2a 13.2b 13.3a 13.3b	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films	HTSUKI and M. UTLAUT 343 344 346 347 352
13.1 13.2a 13.2b 13.3a 13.3b	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films	HTSUKI and M. UTLAUT 343 344 346 347 352
13.1 13.2a 13.2b 13.3a 13.3b 13.3c	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination	HTSUKI and M. UTLAUT 343 344 346 347 352 355
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3c	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants	HTSUKI and M. UTLAUT 343 344 346 347 352 355 355
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3c 13.3d 13.4	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom	HTSUKI and M. UTLAUT 343 344 346 347 352 355 355 357 357
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3c 13.3d 13.4 13.5	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom Some Examples of Single Atom Microscopy	HTSUKI and M. UTLAUT 343 344 346 347 352 355 355 357 357
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3d 13.4 13.5 13.6	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom Some Examples of Single Atom Microscopy Conclusion	HTSUKI and M. UTLAUT 343 344 346 347 352 355 355 357 357 360 366
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3d 13.4 13.5 13.6 Ackno	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom Some Examples of Single Atom Microscopy Conclusion wledoment	HTSUKI and M. UTLAUT 343 344 346 347 352 355 355 357 360 366
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3d 13.4 13.5 13.6 Ackno Refere	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom Some Examples of Single Atom Microscopy Conclusion wledgment nces	HTSUKI and M. UTLAUT 343 344 346 347 352 355 357 357 360 366
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3d 13.4 13.5 13.6 Ackno Refere	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom Some Examples of Single Atom Microscopy Conclusion wledgment nces 14 MICRODIFFRACTION	HTSUKI and M. UTLAUT 343 344 346 347 352 355 357 357 360 366 <i>J.B. WARREN</i>
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3d 13.4 13.5 13.6 Ackno Refere	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom Some Examples of Single Atom Microscopy Conclusion wledgment nces 14 MICRODIFFRACTION Introduction	HTSUKI and M. UTLAUT 343 344 346 347 352 355 355 357 360 360 366 J.B. WARREN 260
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3d 13.4 13.5 13.6 Ackno Refere HAPTER 14.1	ATOMS M. ISAACSON, M.O.I Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom Some Examples of Single Atom Microscopy Conclusion wledgment nces 14 MICRODIFFRACTION Introduction Focused Probe Microdiffraction	HTSUKI and M. UTLAUT 343 344 346 347 352 355 357 360 366 J.B. WARREN 369 271
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3d 13.4 13.5 13.6 Ackno Refere HAPTER 14.1 14.2 14.3	ATOMS M. ISAACSON, M.O.I Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom Some Examples of Single Atom Microscopy Conclusion wledgment nces 14 MICRODIFFRACTION Introduction Focused Probe Microdiffraction Focused Anarture Microdiffraction	HTSUKI and M. UTLAUT 343 344 346 347 352 355 357 360 366 J.B. WARREN 369 371
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3d 13.4 13.5 13.6 Ackno Refere CHAPTER 14.1 14.2 14.3 14.4	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom Some Examples of Single Atom Microscopy Conclusion wledgment nces 14 MICRODIFFRACTION Introduction Focused Probe Microdiffraction Focused Aperture Microdiffraction Focused Aperture Microdiffraction	HTSUKI and M. UTLAUT 343 344 346 347 352 355 357 360 366 J.B. WARREN 369 371 373 373
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3d 13.4 13.5 13.6 Ackno Refere HAPTER 14.1 14.2 14.3 14.4	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom Some Examples of Single Atom Microscopy Conclusion wledgment nces 14 MICRODIFFRACTION Introduction Focused Probe Microdiffraction Focused Aperture Microdiffraction Rocking Beam Microdiffraction Anniications	HTSUKI and M. UTLAUT 343 344 346 347 352 355 357 357 360 366 J.B. WARREN 369 371 373 375
13.1 13.2a 13.2b 13.3a 13.3b 13.3c 13.3d 13.4 13.5 13.6 Ackno Refere HAPTER 14.1 14.2 14.3 14.4 14.5	ATOMS M. ISAACSON, M.O. Introduction Basics - Electron Scattering Basics - Operation Practical Considerations - Electron Optics Probe Formation Further Stability Requirements Practical Considerations - Specimen Preparation Low Noise Support Films Practical Considerations - Clean Support Films Heavy Atom Contamination Practical Considerations - Organic Contaminants How to Visualize an Atom Some Examples of Single Atom Microscopy Conclusion wledgment nces 14 MICRODIFFRACTION Introduction Focused Probe Microdiffraction Focused Aperture Microdiffraction Rocking Beam Microdiffraction Applications Summery	HTSUKI and M. UTLAUT 343 344 346 347 352 355 357 360 366 J.B. WARREN 369 371 373 375 377

Contents			xiii
CHAPTER	15 CONVERGENT BEAM ELECTRON DIFFRACTION	J.W. STEEDS	
15.1	Introduction	387	
	Development of Convergent Beam Diffraction		
	The Microscope		
	TEM Mode		
	STEM Mode		
	Intermediate Configurations		
	Effects Connected with the Specimen		
	Beam Broading		
	Beam Heating		
	Perfection of the Specimen		
	Contamination		
	Goniometry		
15.2	The Dimensional Electron Diffraction	395	
	Higher Order Laue Zones		
	Diameters of Holz Rings		
	Indexing and Origin of Holz Lines		
	i Indexing		
	ii Origin of Lines		
	Lattice Parameter Determination		
	Determination of the Reciprocal Lattice		
	Macaurament of Chemical Variations and Strains		
15.2	Constal Delate and Constant Constants	107	
15.5	Crystal Foint and Space Groups	400	
	Use of High Symmetry Zone Axes		
	Point Group Determination		
	Space Group Determination		
	Handedness of a Crystal		
15 4	A tomio A mongomento	410	
15.4	Atomic Arrangements	412	
	Atomic String Approximation		
15.5	Finger Drinking Techniques	417	
15.5	ringer running leconiques	416	
15.6	Crystal Potential and Thickness Determination	417	
Ackno	wledgments		

## CHAPTER 16 RADIATION DAMAGE WITH BIOLOGICAL SPECIMENS AND ORGANIC

References

	MATERIALS	ROBERT M. GLAESER
16.1	Introduction	423
16.2	Primary Events in Radiation Physics and Radiation Chemistry	425
16.3	Empirical Studies of Radiation Damage Effects Measured Under	Conditions
	Used in the Electron Microscope	428
16.4	Signal-to-Noise Considerations at Safe Electron Exposures	429
16.5	Additional Processes of Radiation Damage that Occur at Very Hi	igh Electron
	Exposures	432
Ackn	owledgments	
Refer	ences	

# CHAPTER 17 RADIATION EFFECTS IN ANALYSIS OF INORGANIC SPECIMENS BY TEM L.W. HOBBS 17.1 Introduction 437

Radiation Damage in Com	pact Lattices
Electron-Atom Inelastic In	teraction
Electron-Beam Heating	
Charge Acquisition by Inst	Ilating Specimens

		Contents
17.2	Knock-On Displacement Displacement Energy	444
	Momentum Transfer	450
17.3	Radiolysis Electronic Excitations	450
	Electronic Excitations Energy-to-Momentum Conversion	
	Influence of Temperature, Impurity and Radiation Flux	
17.4	Degradation Kinetics	457
17.5	Radiation-Induced Structural Changes During Analysis	460
	Frenkel Defect Condensation	
	i Planar Aggregates	
	Ordering and Disordering	
	Segregation and Precipitation	
17.6	Minimizing The Effects of Irradiation	472
	Reducing the Electron Dose	
1.7.7	Reducing the Temperature	176
1/./ Defeur	Conclusions	470
Kelere	ences	
CHAPTER	18 BARRIERS TO AEM: CONTAMINATION AND ETCHING	J.J. HREN
10 1	Introduction	481
10.1	Introduction Some Definitions	481
18.2	Farly Observations of Contamination	487
18.5	The Nature of the Contaminant	483
18.5	Relationshin Retween Contamination and Etching	484
18.6	Surface Diffusion and Beam Size Effects	486
18.7	Recent Studies of Contamination and Etching	487
18.8	Summary of Phenomenological Observations	490
18.9	The Mechanisms of Contamination	491
1000	Physiosorption of Hydrocarbon Molecules	
	Surface Diffusion of Hydrocarbon Molecules	
	Polymerization and Fragmentation of Hydrocarbon Molecules in the Electr	ron Beam
	Electrical Gradients in the Surface	
18.10	The Mechanisms of Etching	495
	Physiosorption of a Potentially Reactive Gas	
	Activation of the Reactive Gas by Electrons	
	Specimen or Contaminant Molecules that Will React with the Excited Phys	iosorbed Gas
19 11	Working Solutions: Proven and Potential	407
18.17	Some Effects of Contamination and Etching on AEM	500
Refer	Some Encers of Containington and Etening on AEM	500
iteren (		
CHAPTER	19 MICROANALYSIS BY LATTICE IMAGING	ROBERT SINCLAIR
19.1	Introduction	507
19.2	Theoretical Considerations	508
	Fringe Imaging	
	Specimen-Related Parameters	
	Microscope Parameters	
10.2	Multi-beam Imaging Evinerimental Procedures	<b>E1E</b>
19.5	Experimental riocedures	515
19.4	Analysis of Fringe images	520
19.5	Composition Determination	521
19.0	Experimental Examples	524
19./		321

19.8	Summary	530		
Ackn	owledgments			
Refe	ences			
Note	on Key References			
CHAPTE	R 20 WEAK-BEAM MICROSCOPY	JOHN B. VANDER SANDE		
20.1	Introduction	535		
20.2	Theoretical Background	536		
	Strong-Beam Images			
	Weak-Beam Images			
20.3	The Practice of Weak-Beam Microscopy	539		
	Instrumental Needs			
	Establishing a Weak-Beam Condition			
	i The Ewald Sphere Construction for Strong-Beam Microscopy			
	ii Ine Ewald Sphere Construction for Weak-Deam Microscopy			
20.4	Applications of Wook Beem Microscony	543		
20.4	Separation of Partial Dislocations	545		
	Dense Defect Arrays: Dislocation Dipoles, Dislocation Tangles, and	Dislocation Cell Walls		
	Precipitation on Dislocation Lines: Second Phase Particle Interfaces	8		
	Comments			
Ackn	owledgments			
Refe	ences			
CHAPTE	3 21 THE ANALYSIS OF DEFECTS USING COMPUTER	R SIMULATED		
UIII 12	IMAGES	PETER HUMBLE		
21.1	Introduction	551		
21.2	Theory and Computational Considerations	552		
21.3	Experimental Method and the Collection of Information	559		
21.4	Examples of the Use of Simulated Images in the Analysis o	f Defects 560		
21.5	The Context of this Technique in AEM	571		
Refe	ences			
Major References				

CHAPTER 22 THE STRATEGY OF ANALYSIS

22.1	Introduction	575		
22.2	Where to Begin?	575		
22.3	Specimen Type Strategy	576		
22.4	Identification-Solving Unknown Phases and Structures with AEM Input	583		
22.5	AEM and Complimentary Technique Examples	586		
	Al-Cu Thin Film Corrosion			
	Al-Cr Films and Al-Hf Films			
	Organic Residue on Fired Thick Film Conductors			
	Premature Collector - Base Breakdown			
Ackno	wledgments			
References				

RON ANDERSON and J.N. RAMSEY